

Update on Multi-Megabar Ramp Compression at Z

Jean-Paul Davis

with Marcus D. Knudson, Ray W. Lemke, and others

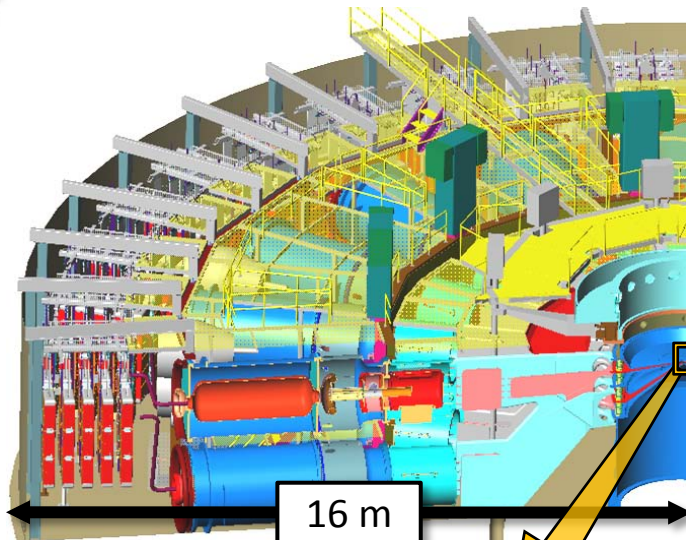
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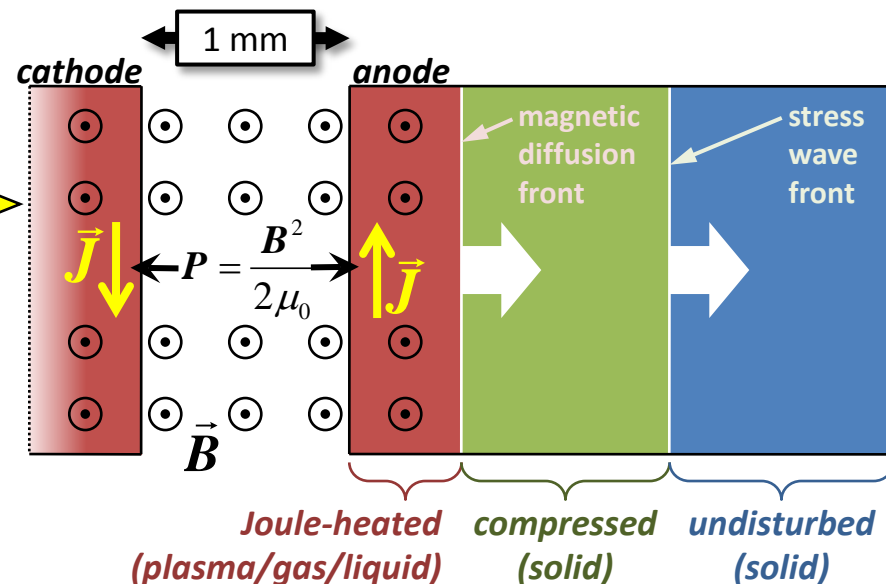
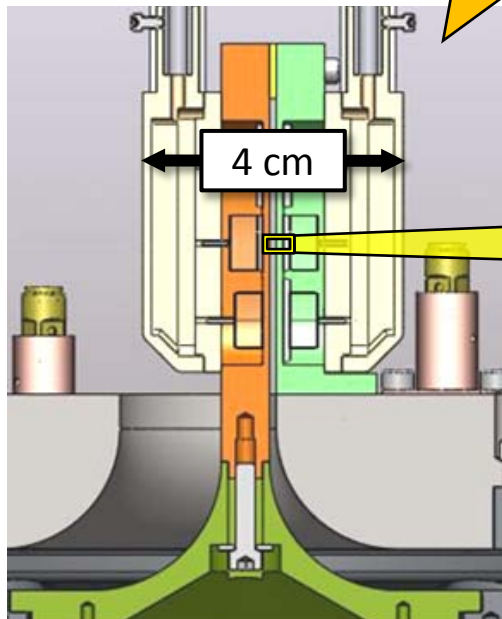


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Refurbished Z machine & stripline load enable accurate ramp-compression experiments to > 300 GPa



- current pulse of up to 26 MA delivered to parallel flat-plate electrodes shorted at one end
- magnetic ($\mathbf{J} \times \mathbf{B}$) force induces ramped stress wave in electrode material
- stress wave propagates into ambient material, de-coupled from magnetic drive
- controllable pulse shape, rise time 100-700 ns
- identical magnetic loading of sample pairs





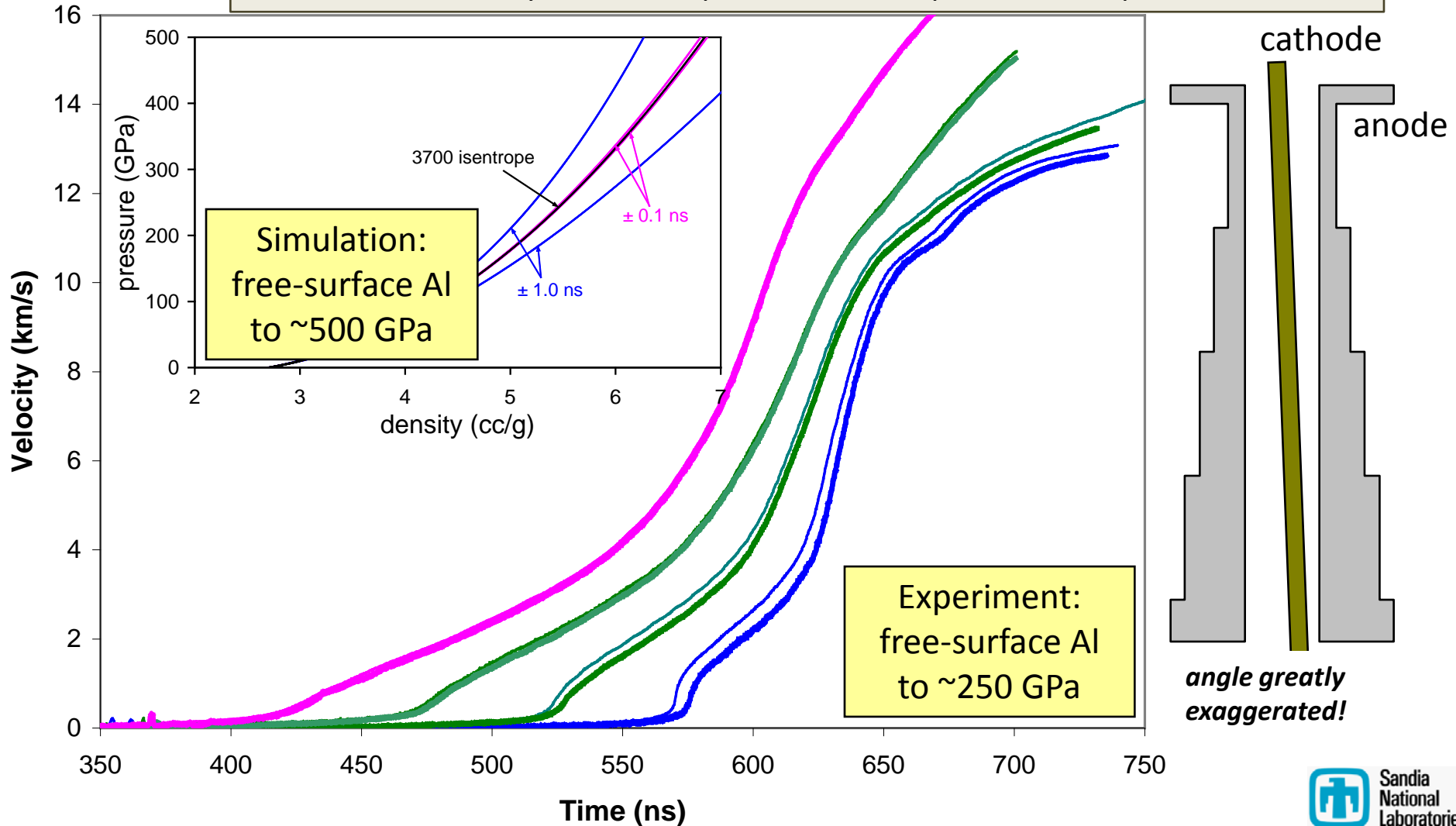
OUTLINE

- 1. Stripline load development (6 slides)**
- 2. Pulse shaping (2 slides)**
- 3. Data analysis (4 slides)**
- 4. Preliminary results on tantalum (2 slides)**

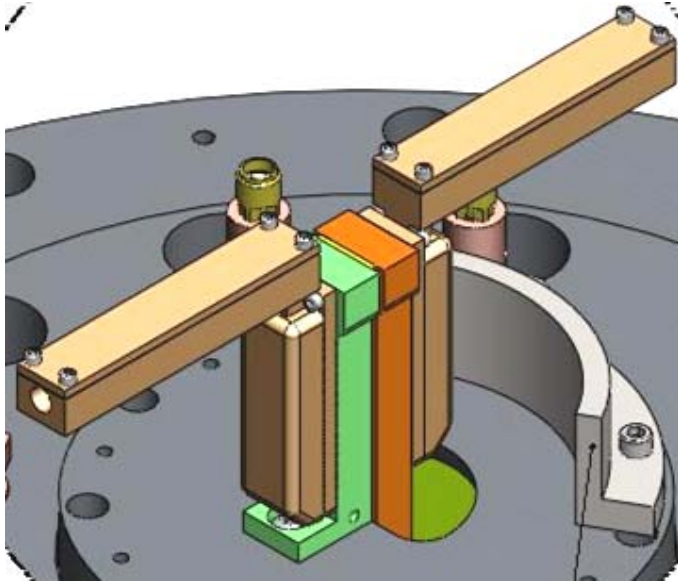
Small misalignments of coaxial anode/cathode geometry can cause significant apparent time shifts

Standard ramp-compression load design on pre-refurbished Z

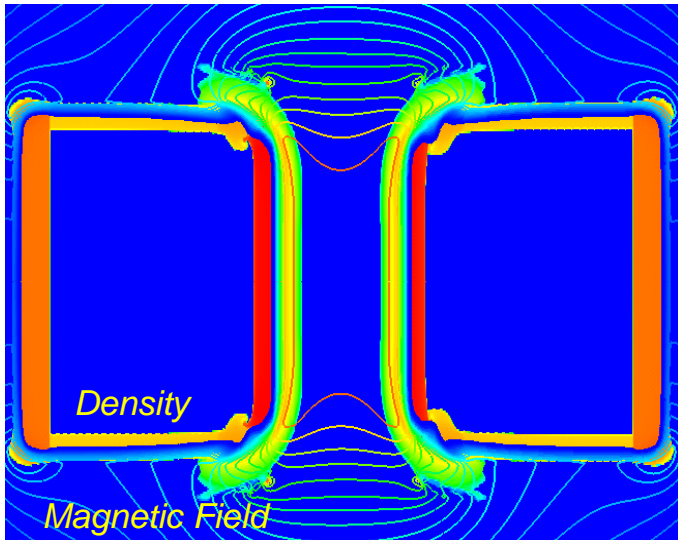
- samples on separate anodes, two coupled A/K gaps
- 1% uncertainty in stress requires electrodes parallel to $< 5 \mu\text{m}$ across 25 mm



New stripline geometry offers several advantages

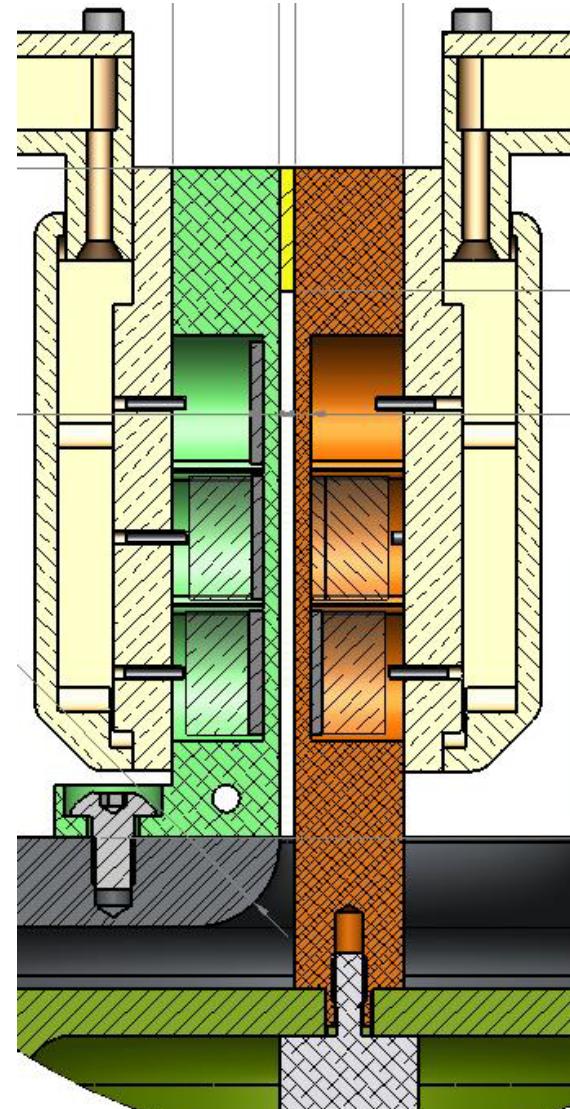


- insensitive to vertical angular misalignment
- single B-field waveform drives two samples
- higher magnetic pressure for given current
- larger lateral extent of uniform 1-D flow

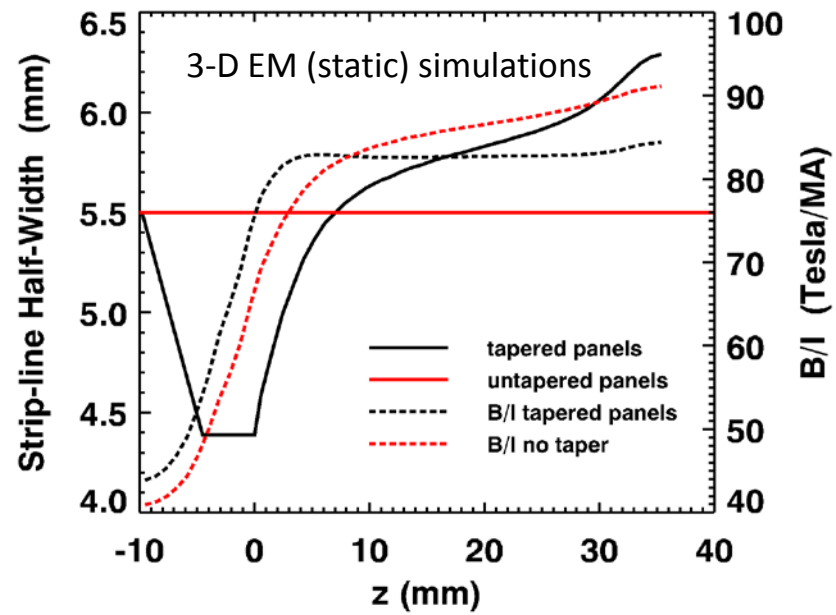
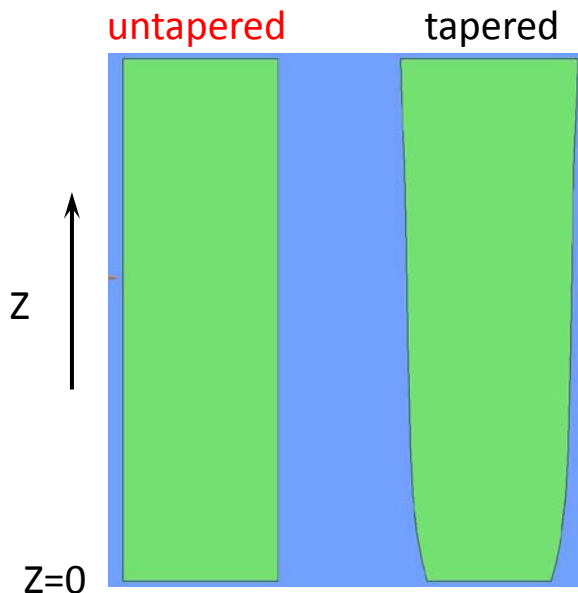
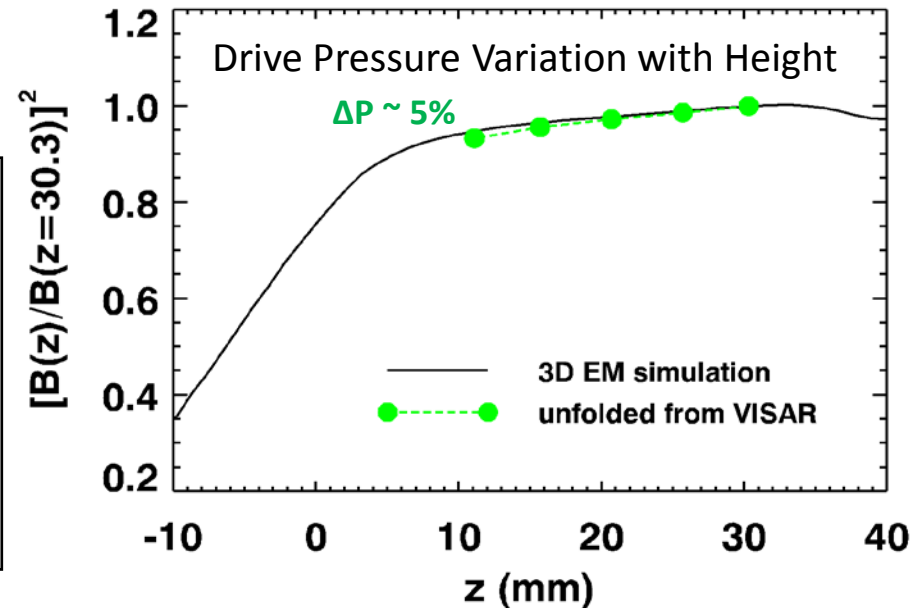
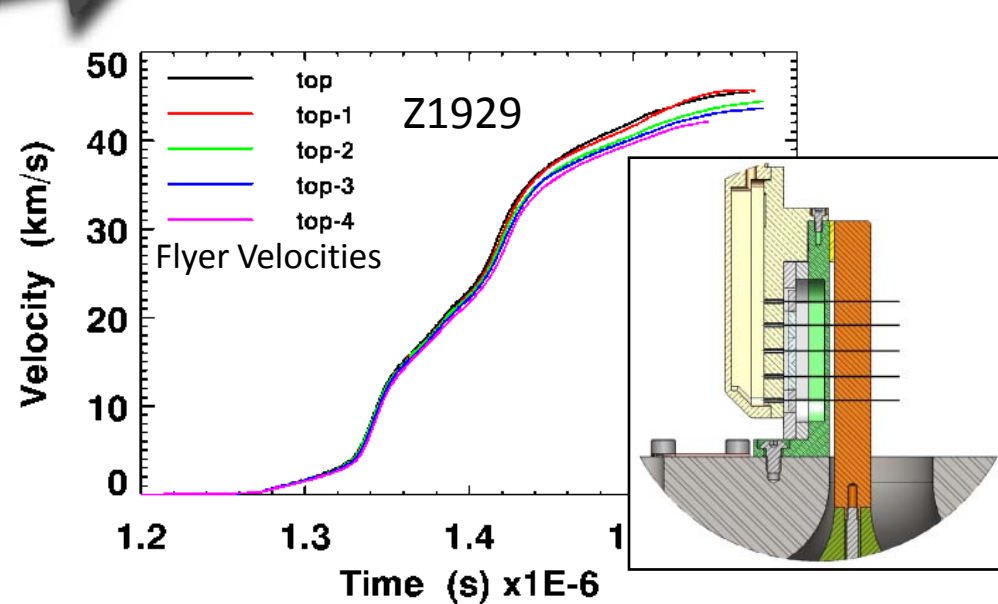


Unconfined B-field:

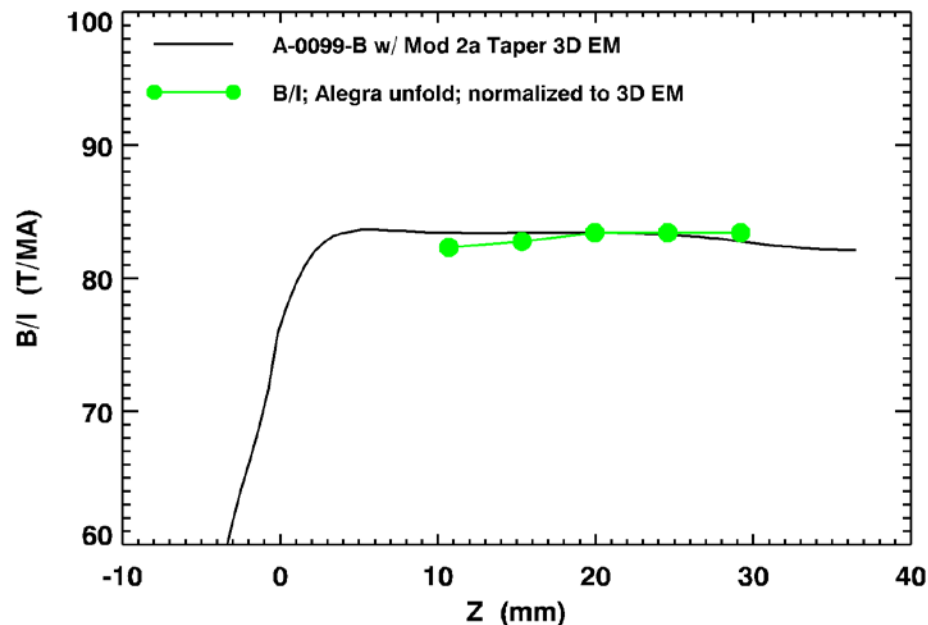
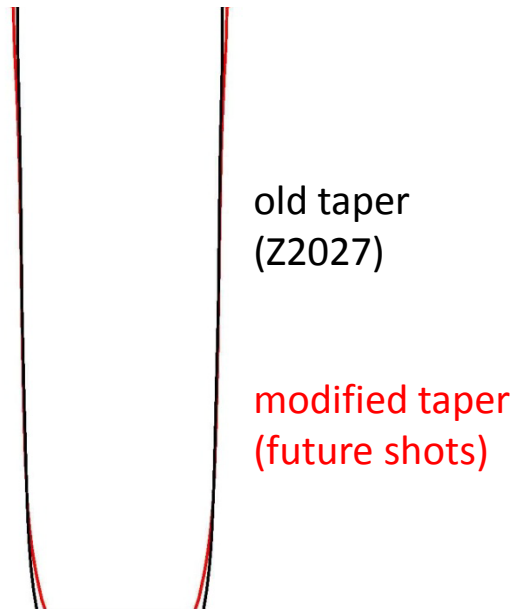
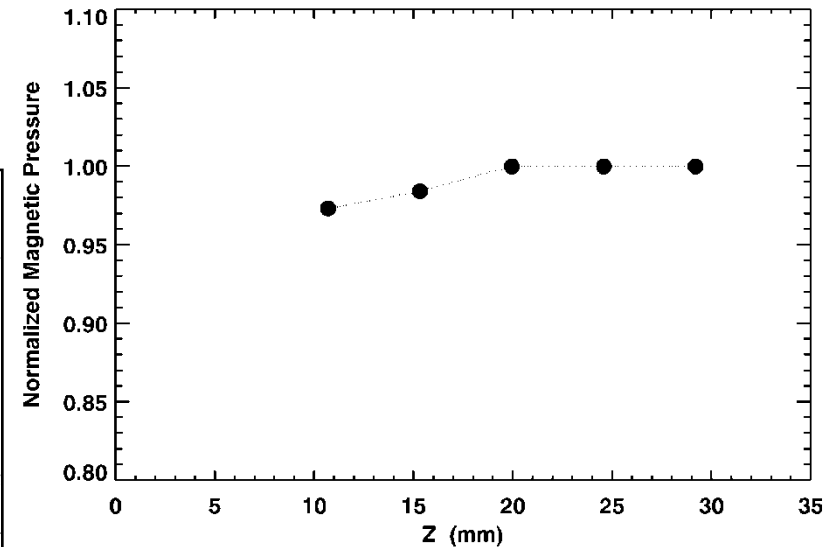
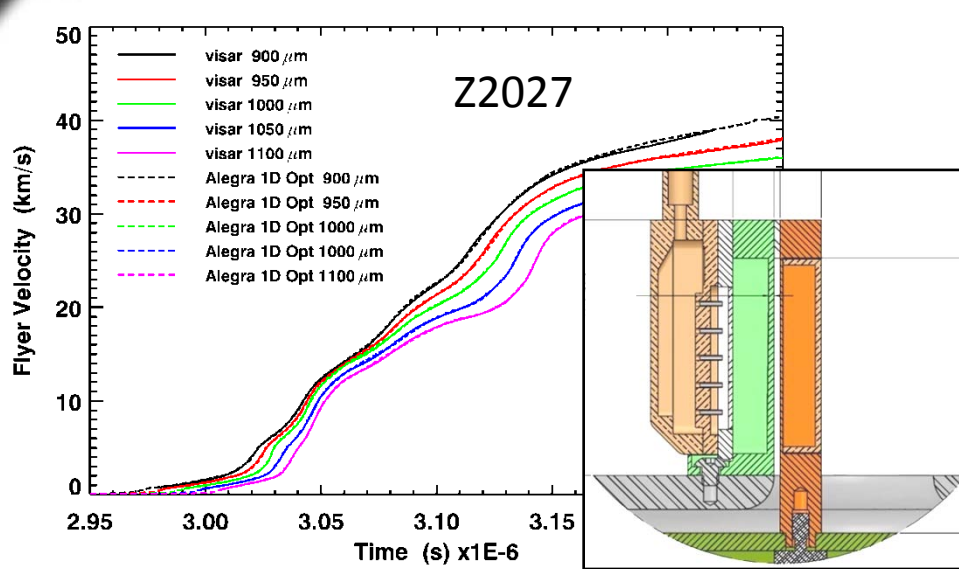
- vertically non-uniform distribution of current inside/outside the gap
- shielding of diagnostics and samples



Measurement of vertical non-uniformity of B-field shows need for functional tapering of stripline width



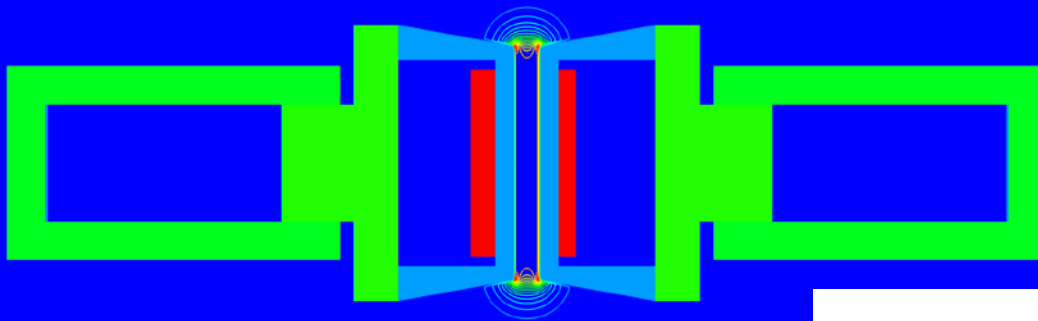
Semi-empirical functional tapering of stripline width should eliminate vertical non-uniformity of B-field



Simulations predict highly uniform B-field in the lateral and normal directions over most of the gap

$t=2.6004e-06$ s

Z1844



Magnetic Field (line contours)
Density (filled contours)

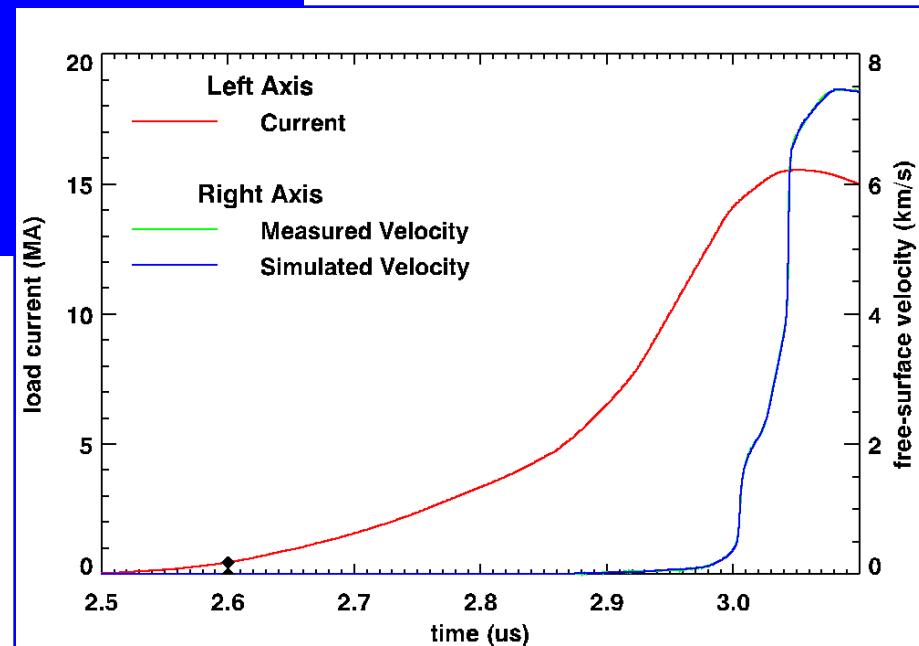
2-D Alegra-MHD:

Resistive MHD

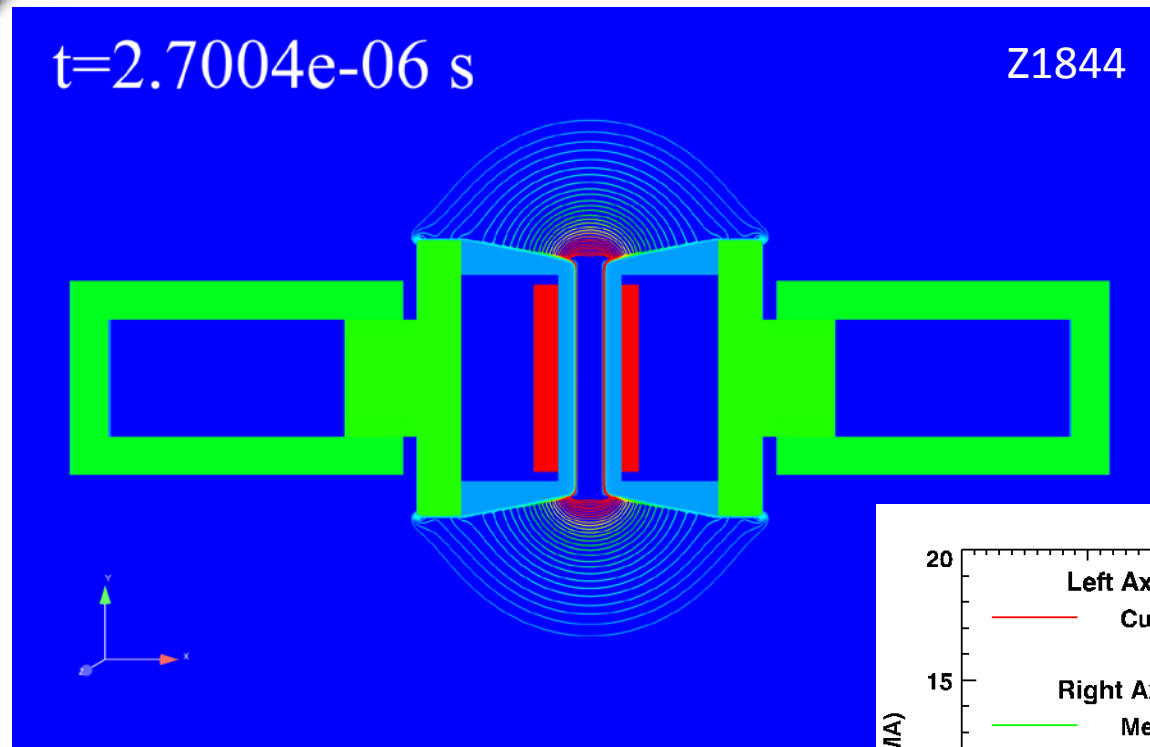
QMD/LMD conductivity

Sesame EOS

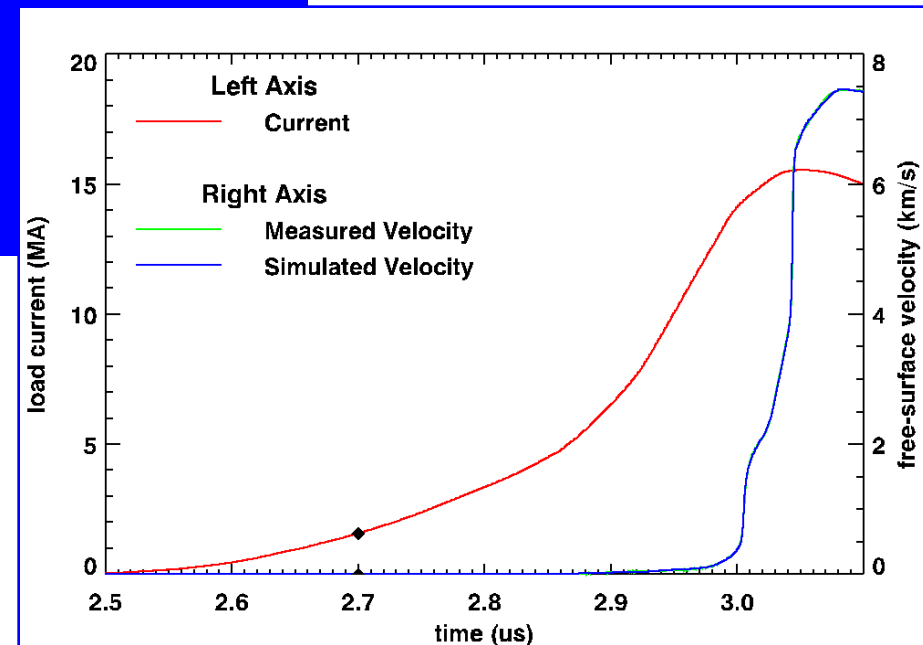
Circuit model



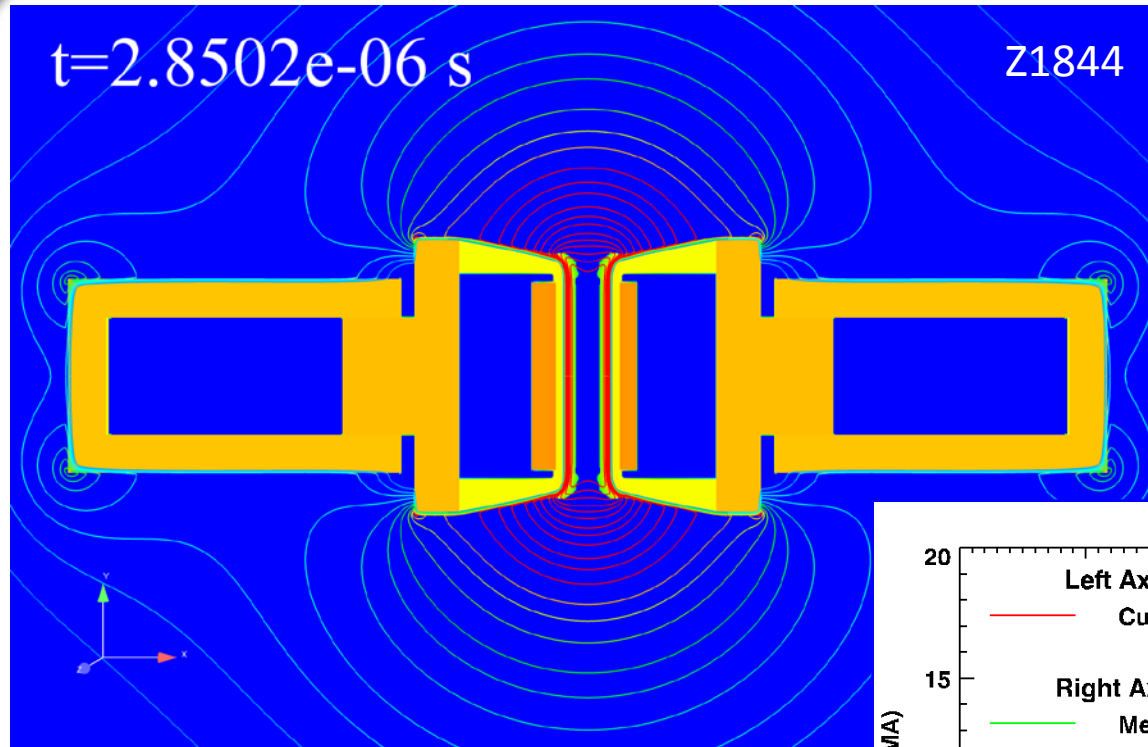
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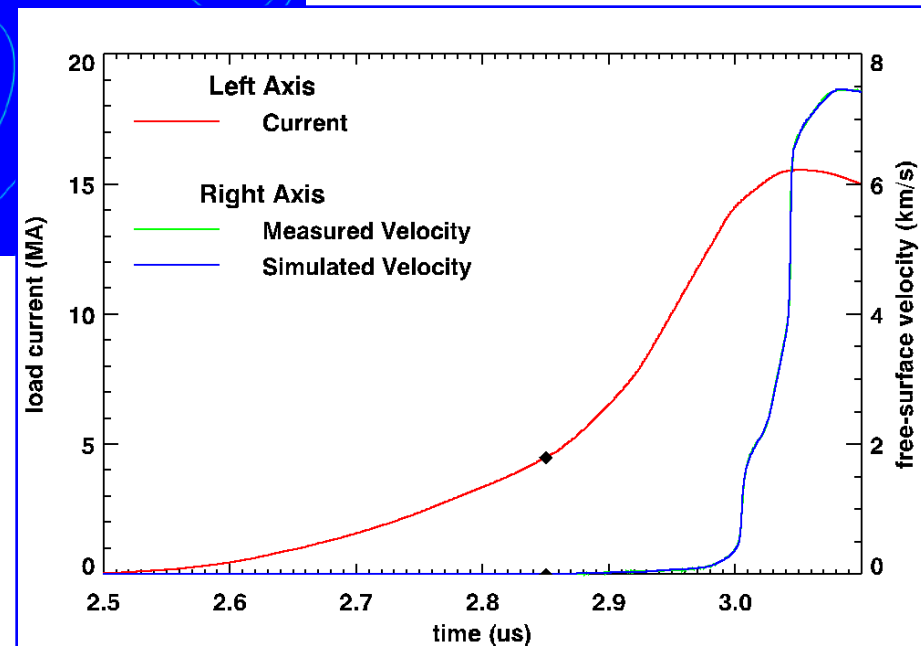
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Density (filled contours)



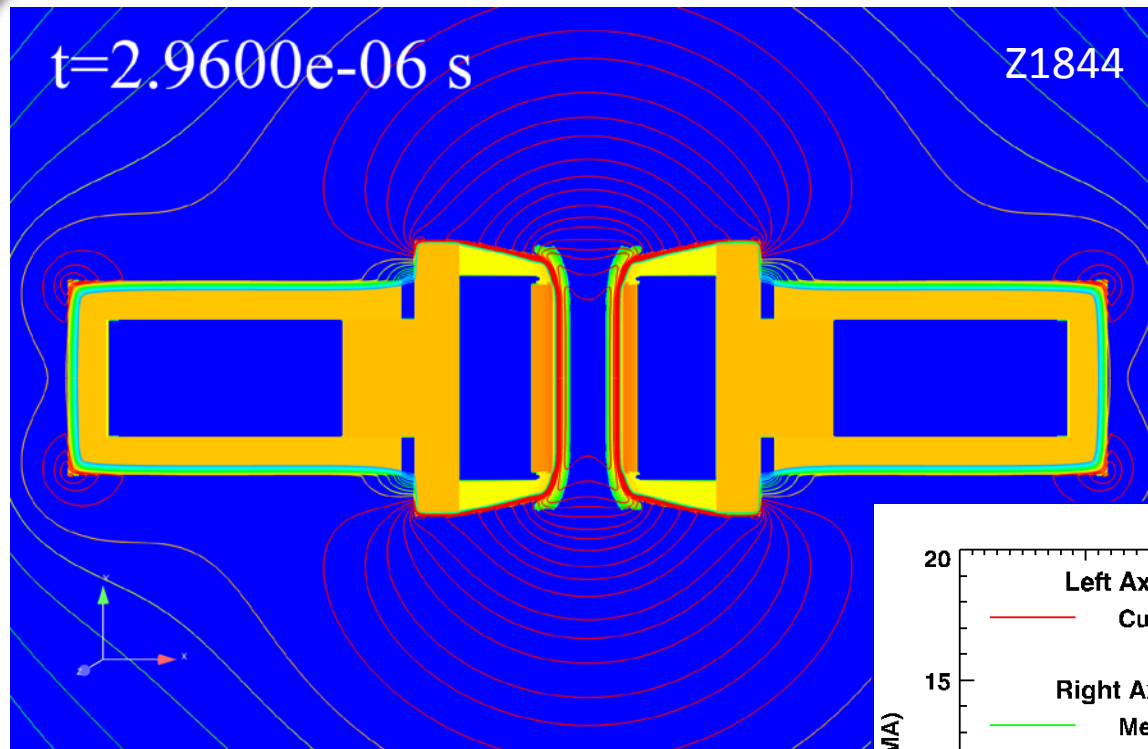
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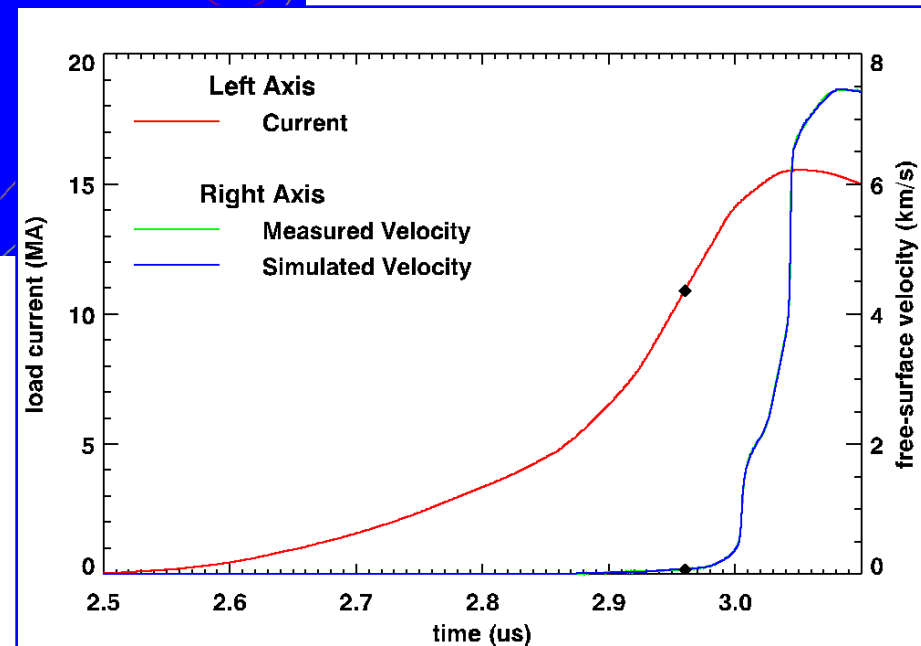
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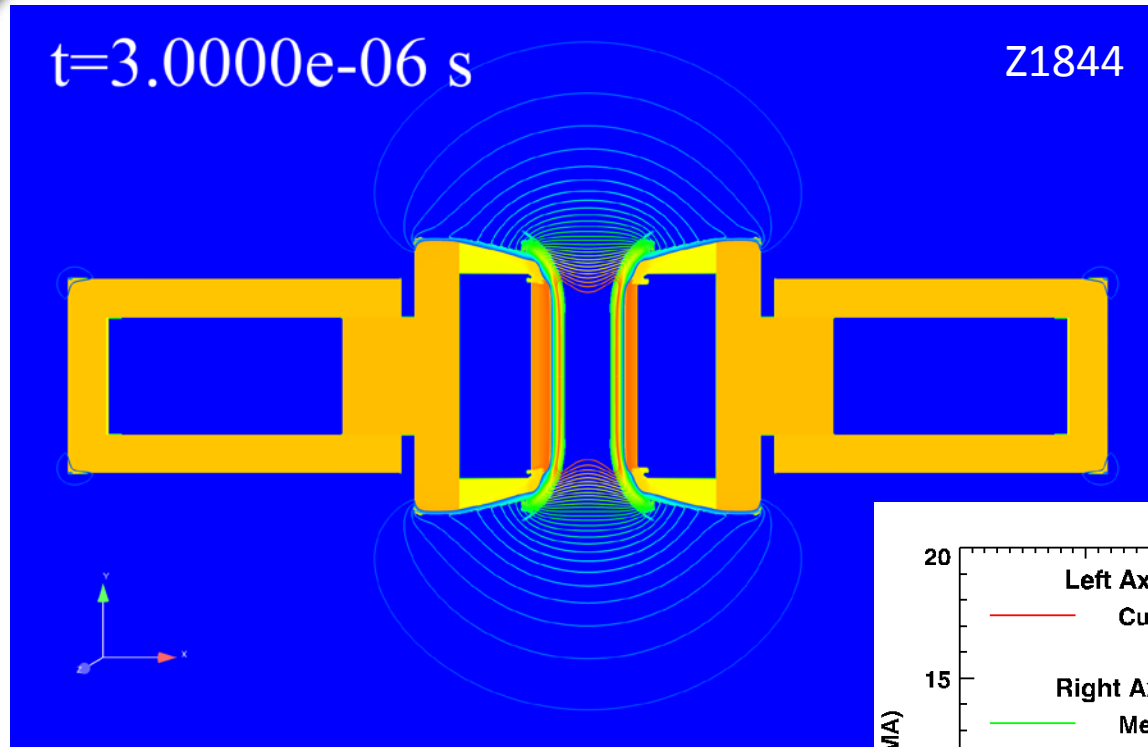
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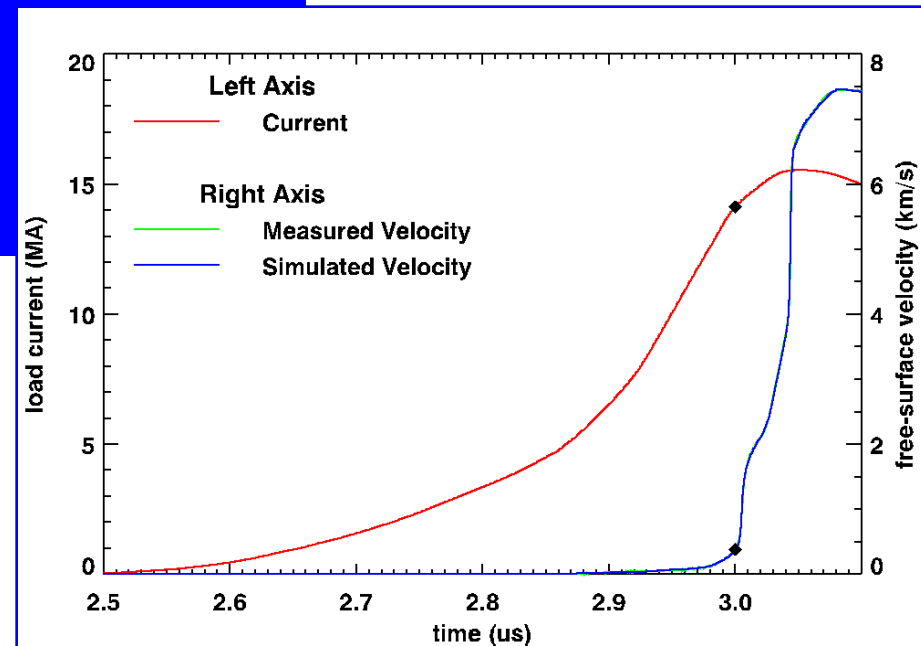
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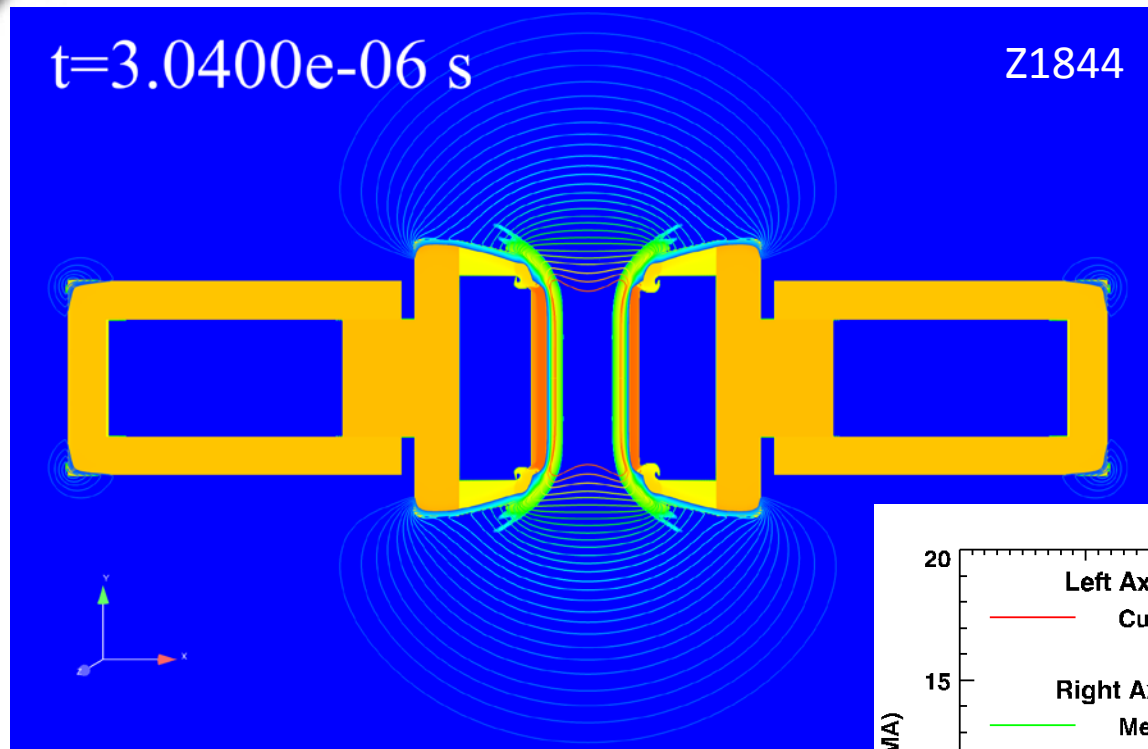
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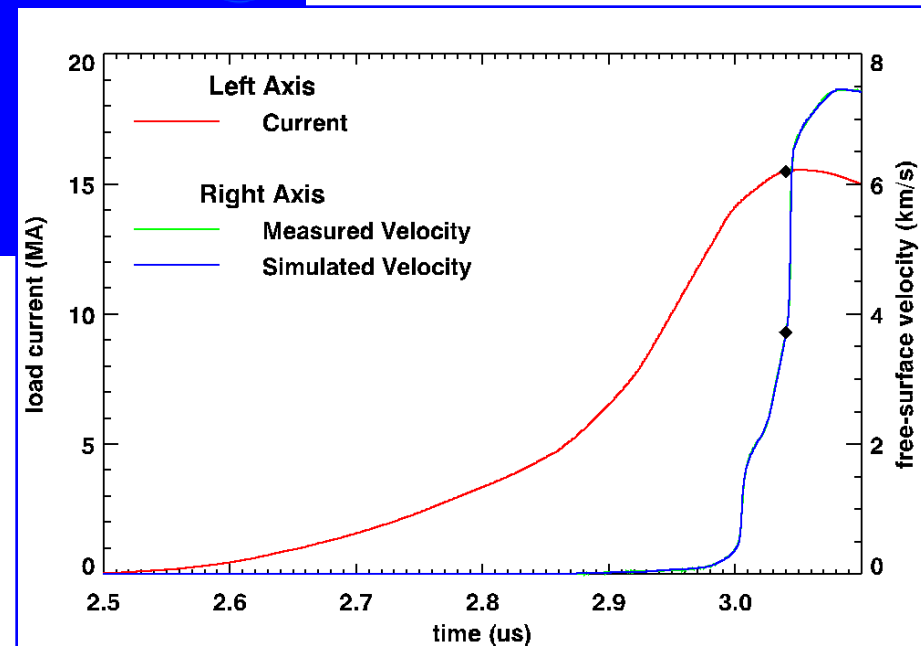
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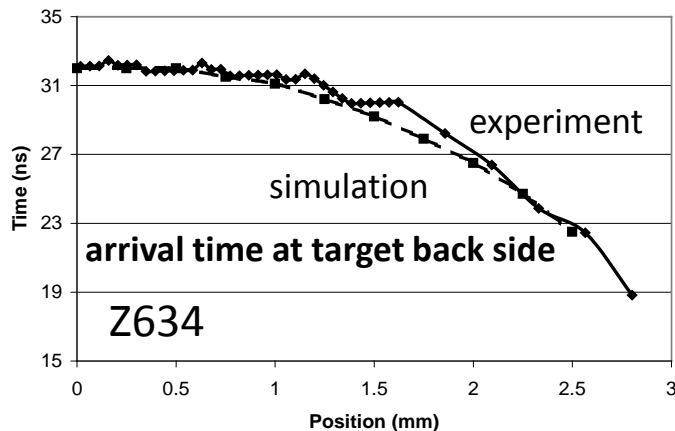
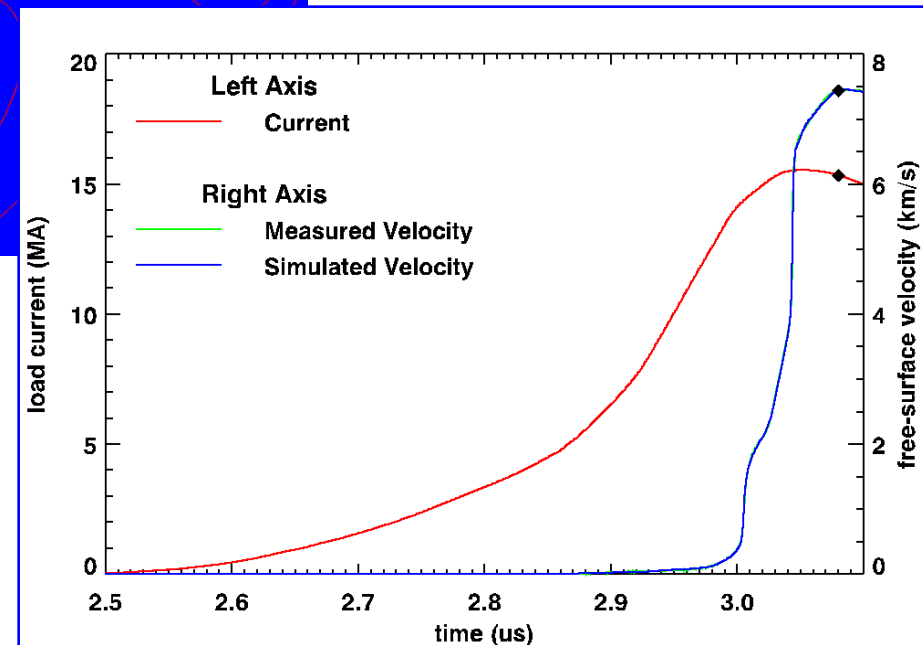
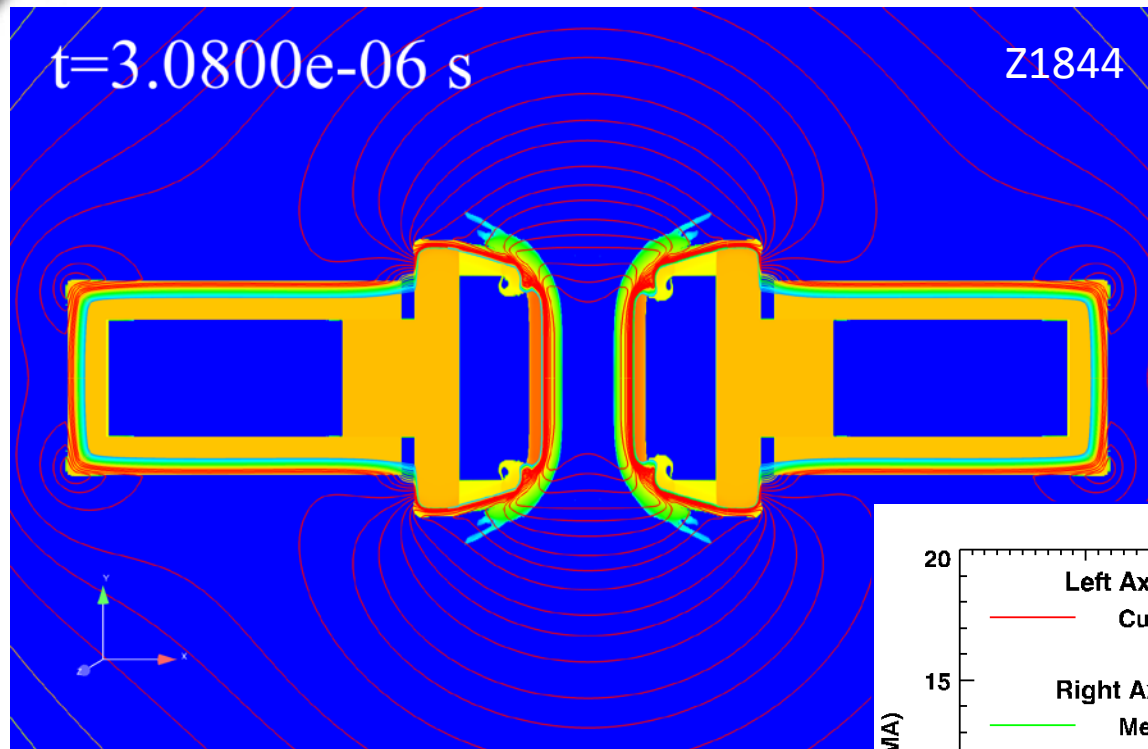
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Magnetic Field (line contours)
Density (filled contours)



Simulations predict highly uniform B-field in the lateral and normal directions over most of the gap



VISAR fiber darkening issues have been addressed

X-rays generated at corners
inside inner-MITL feed?

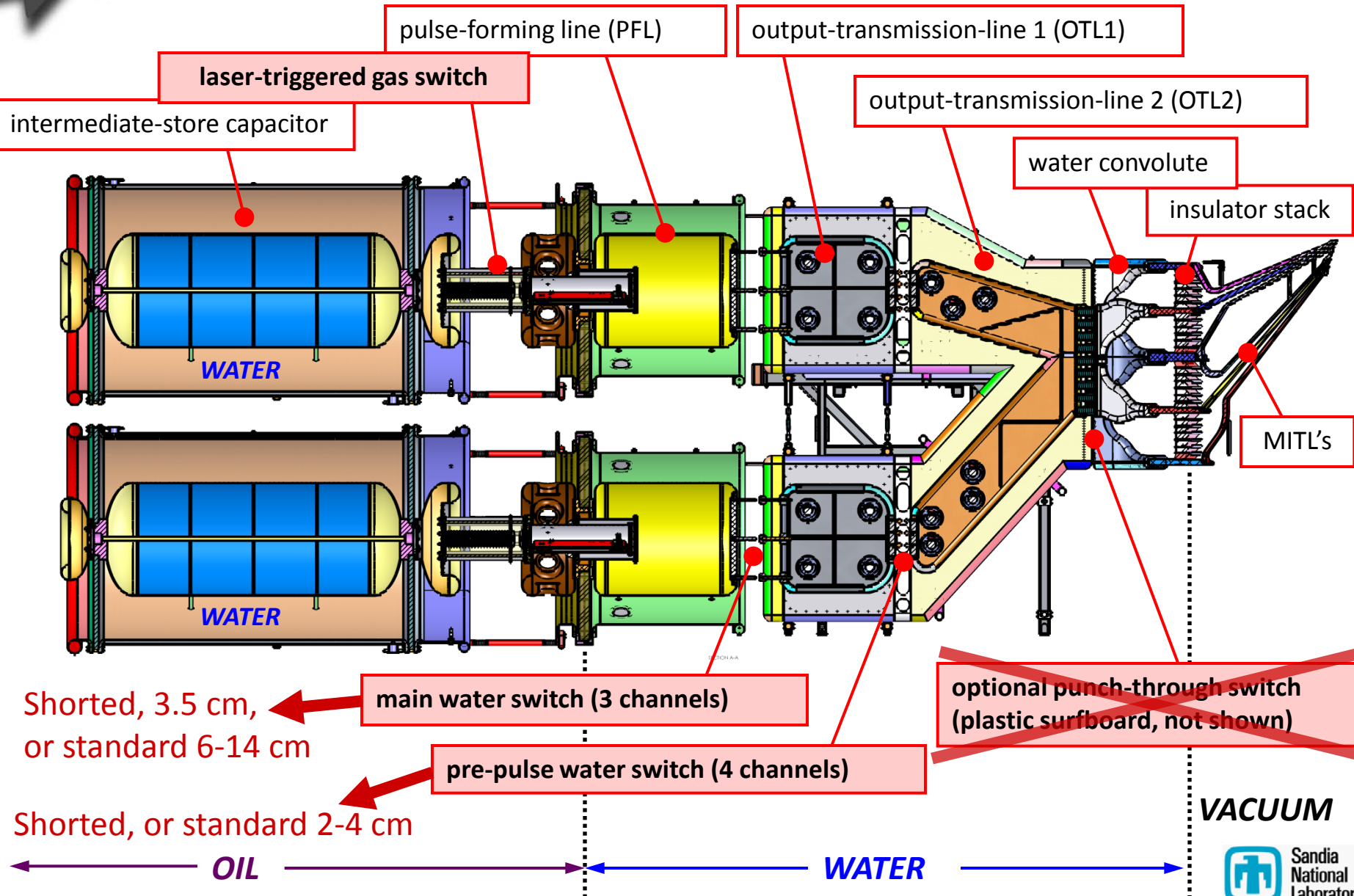
“D-hole” anode opening
decreased to 4-mm
minimum A-K distance



“Radial” feed for
axisymmetric-to-stripline
transition



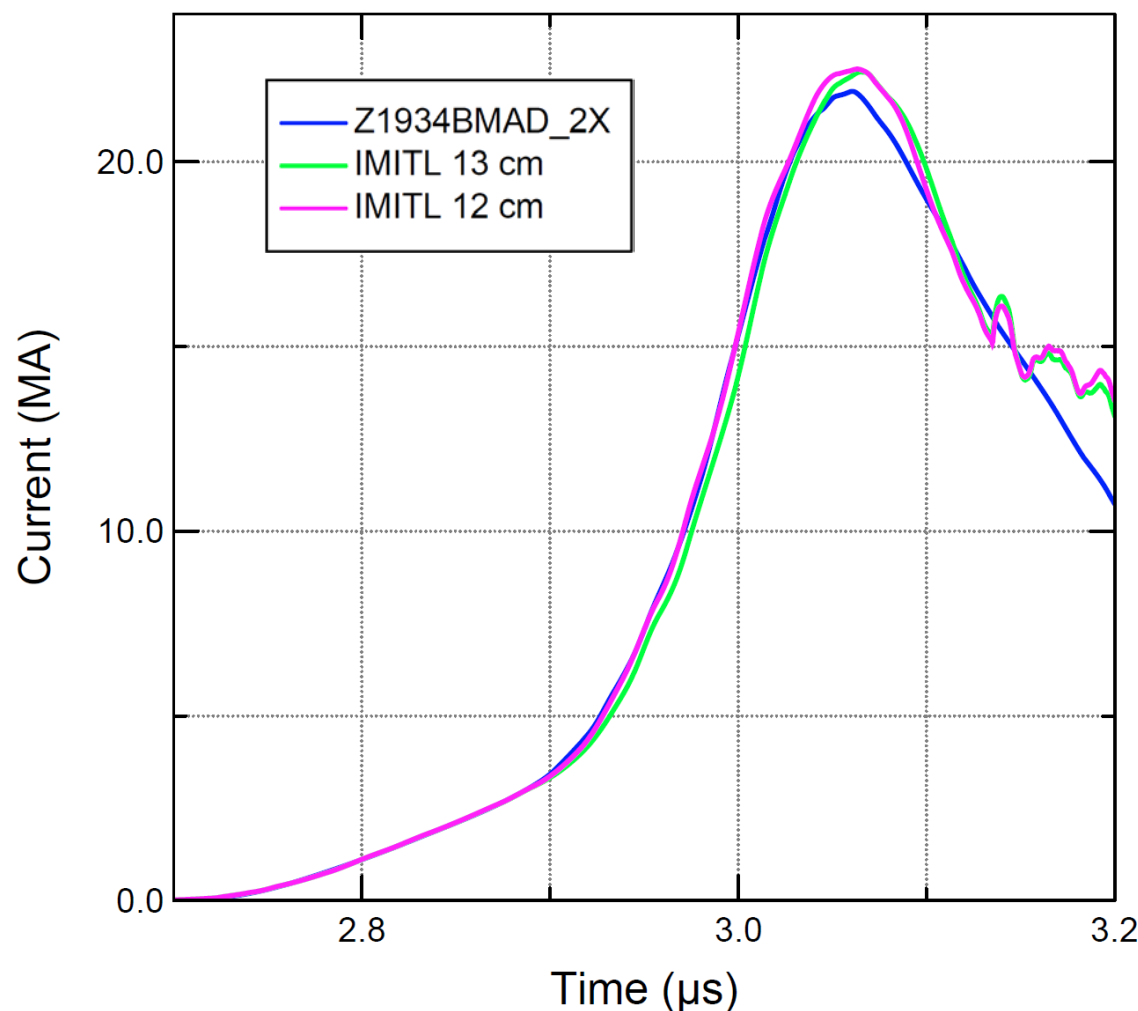
Shaped pulses are obtained by staggering gas-switch times and modifying water switches



Recent improvements to the Bertha circuit model of Z have increased accuracy of predictions

Recovers effect of 1-cm change in main water-switch gaps of 30 short-pulse lines!

85-kV standard = 13cm gap
Z1934 at 12cm instead
(standard for 80-KV on Z1933)



- working with L-3 Communications on final version of model
- calibrate pulse-forming section against flat-MITL shots
- will include 2-D transmission-line sections (OTL2, stack and outer MITLs)

Inverse Lagrangian analysis of velocity from two samples gives quasi-isentropic stress-density response



VISAR

thick sample

electrode

A-K gap

electrode

thin sample

VISAR

Inverse Lagrangian analysis of velocity from two samples gives quasi-isentropic stress-density response

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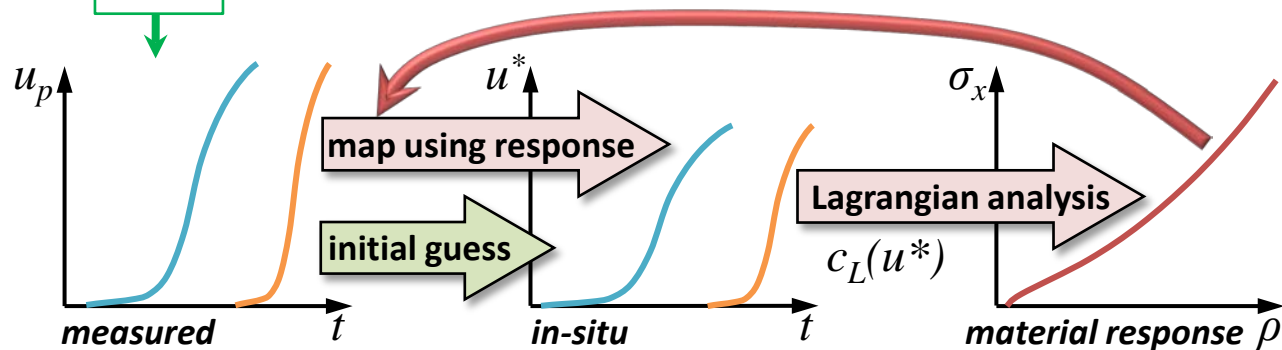
A-K gap

electrode

thin sample

VISAR

1. measure velocity at back faces of two different-thickness samples
2. make initial guess of in-situ $u^*(t)$ at each measurement location
3. determine material response by Lagrangian analysis of in-situ $u^*(t)$
4. use material response to map measured $u_p(t)$ to in-situ $u^*(t)$
5. repeat steps 3-4 until material response converges



- assumes isentropic, simple-wave behavior
- **valid ONLY while electrode/sample interface states identical**

Inverse Lagrangian analysis of velocity from two samples gives quasi-isentropic stress-density response

VISAR

thick sample

electrode

A-K gap

electrode

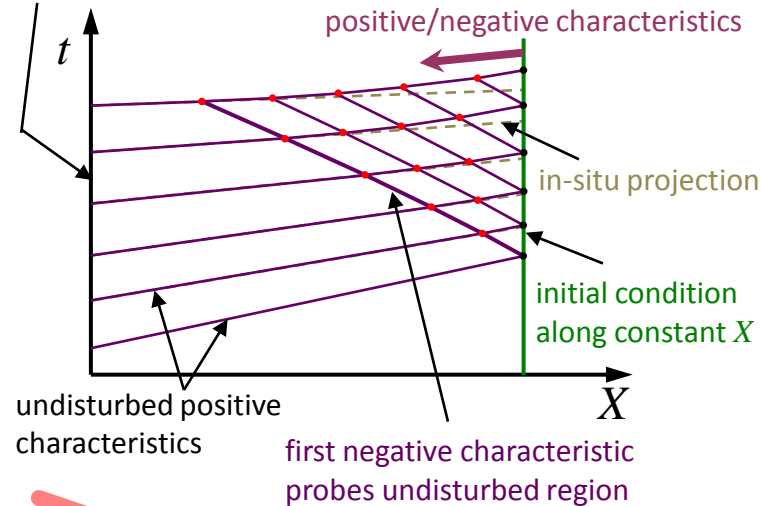
thin sample

VISAR

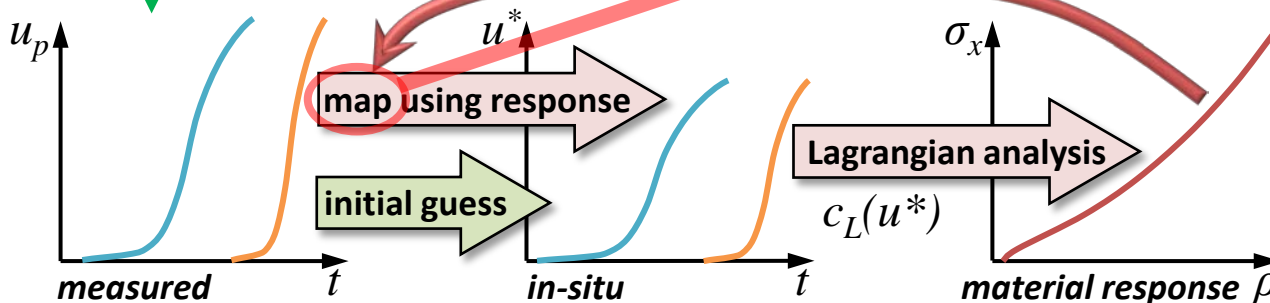
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electrode/sample interface
(unknown state)


find intersections between
positive/negative characteristics



- use Riemann invariants to solve intersections between
 1. negative characteristics projected forward in time
 2. positive characteristics projected backward in time
- project points on 1st negative characteristic forward to measurement position

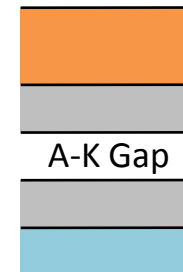


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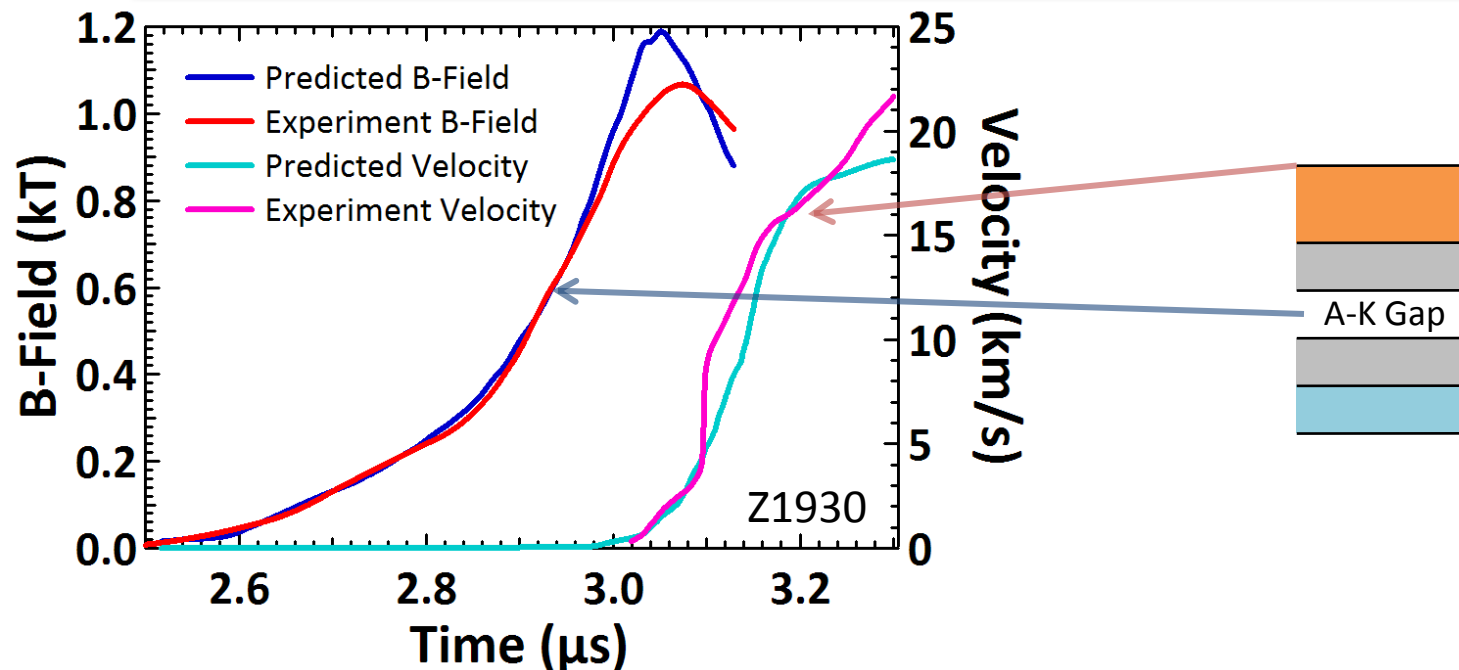
Two-sample approach is limited in accuracy and maximum stress by pulse shape and reverberation

- uncertainty in $c_L = \Delta X / \Delta t$ depends on relative uncertainty in thickness difference
 - must maximize difference in thickness between samples



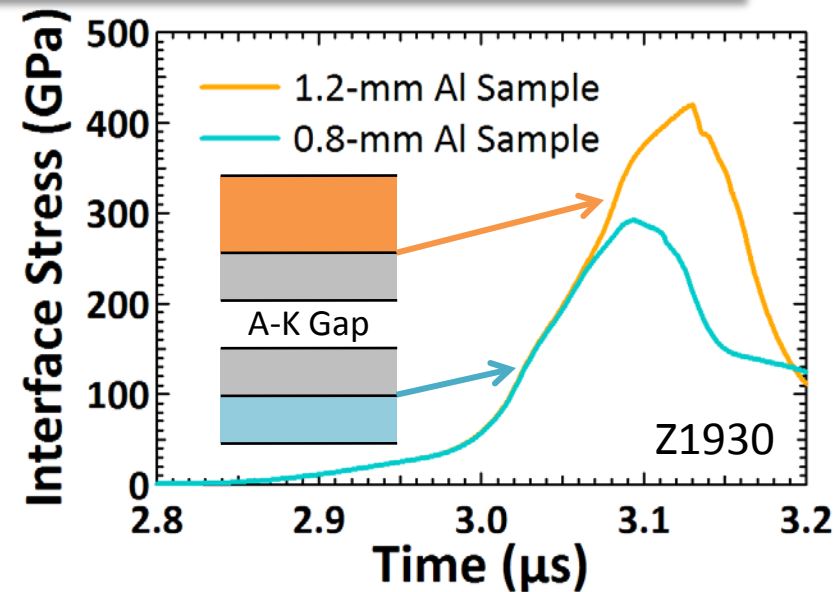
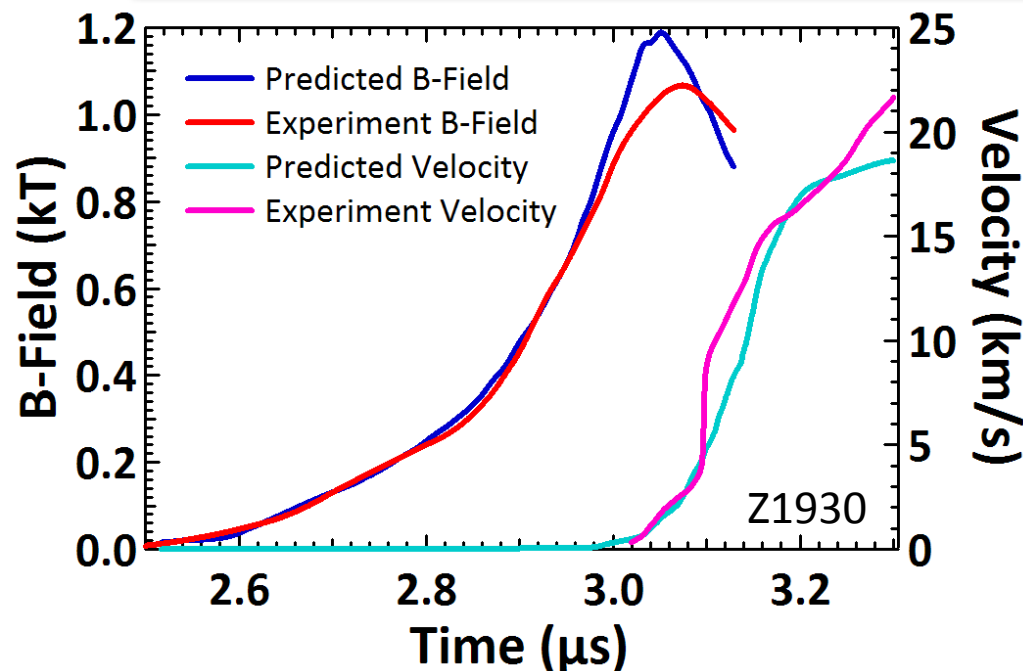
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 - must maximize difference in thickness between samples
- requirement for 1-D shock-free loading limits **maximum thickness**
 - imprecision in pulse shaping makes ideal shock-up distance difficult to attain



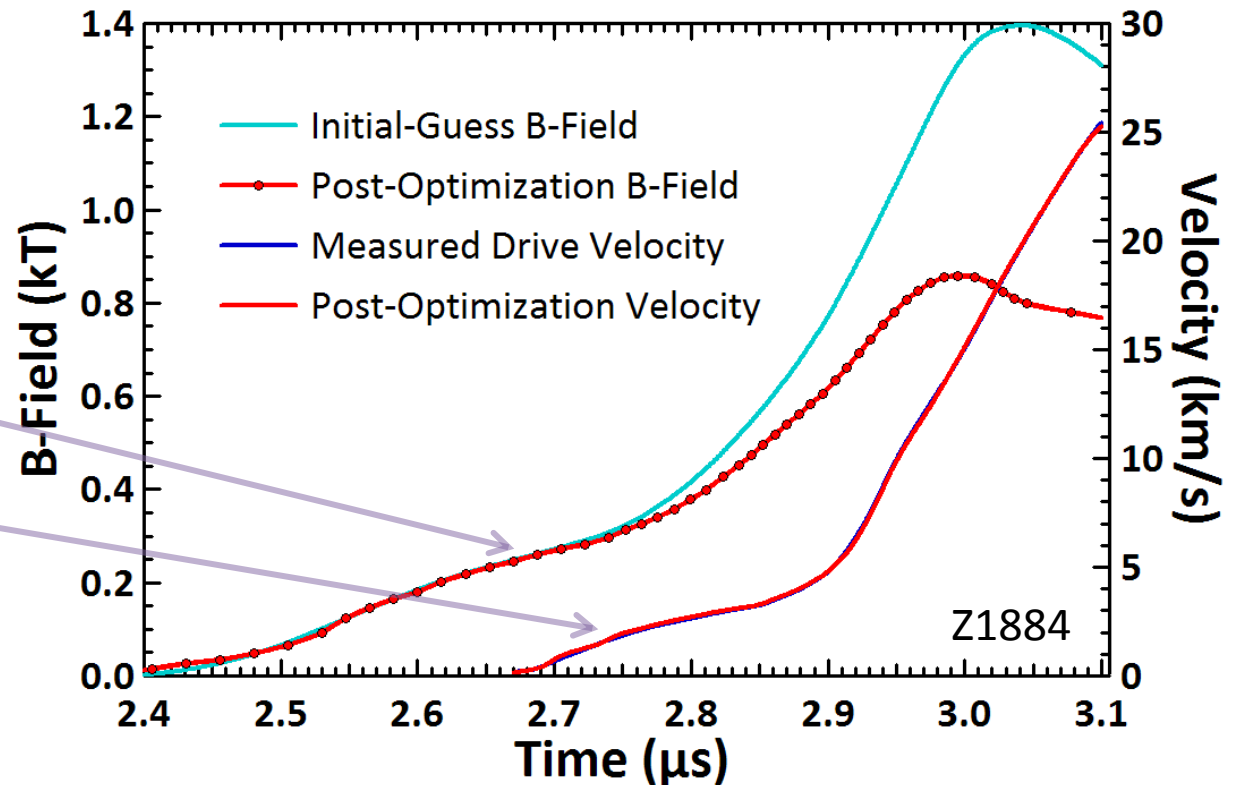
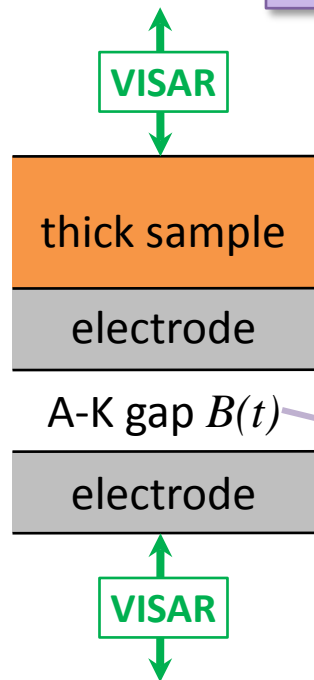
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- requirement for 1-D shock-free loading limits **maximum thickness**
 - imprecision in pulse shaping makes ideal shock-up distance difficult to attain
- arrival of back-surface reflection at sample's front surface (reverberation) limits **minimum thickness** to achieve desired stress state
- increasing rise time to delay shock formation in thick sample reduces peak stress at front surface of thin sample



Optimization technique determines magnetic-field history in A-K gap from electrode “drive” measurement

- Dakota optimization framework drives Alegra 1-D MHD simulations
- $B(t)$ represented by constrained cubic spline (25-50 points) with time shift and stretch factors
- objective function is metric of isometry between simulated and experimental velocity history at electrode back surface

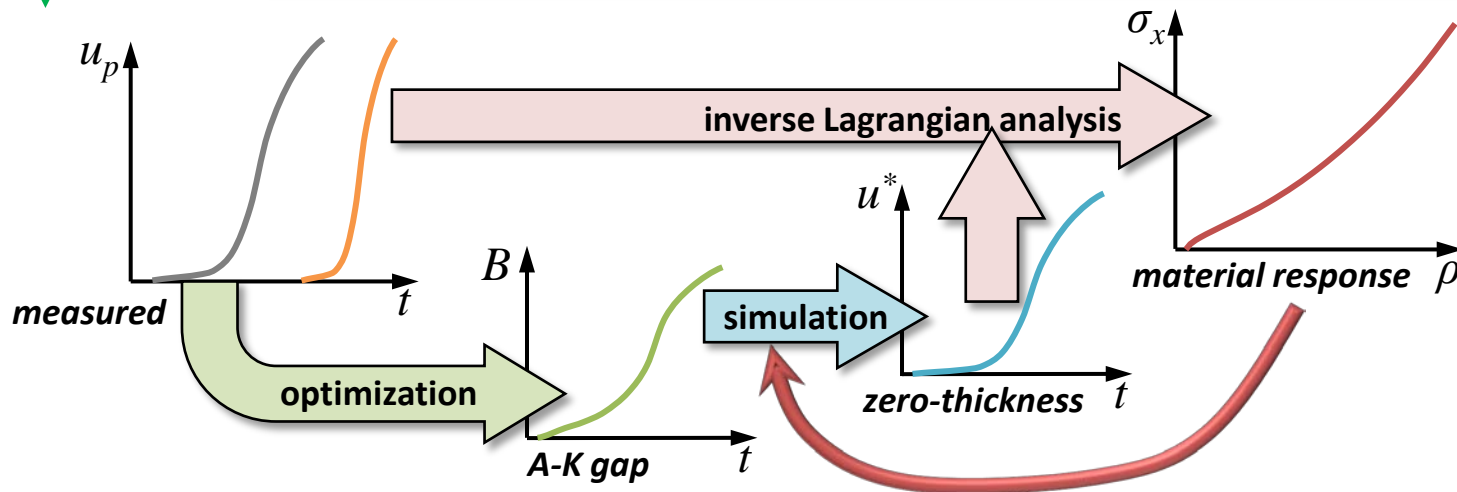
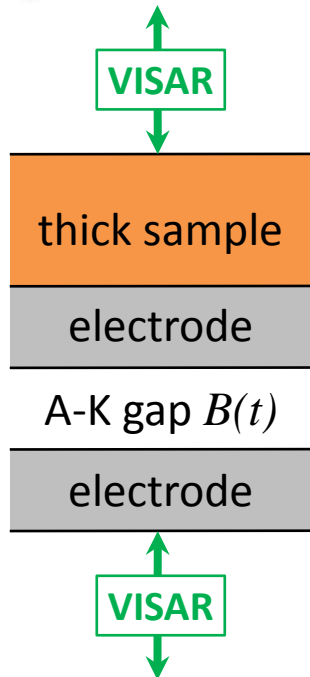


MHD simulations:

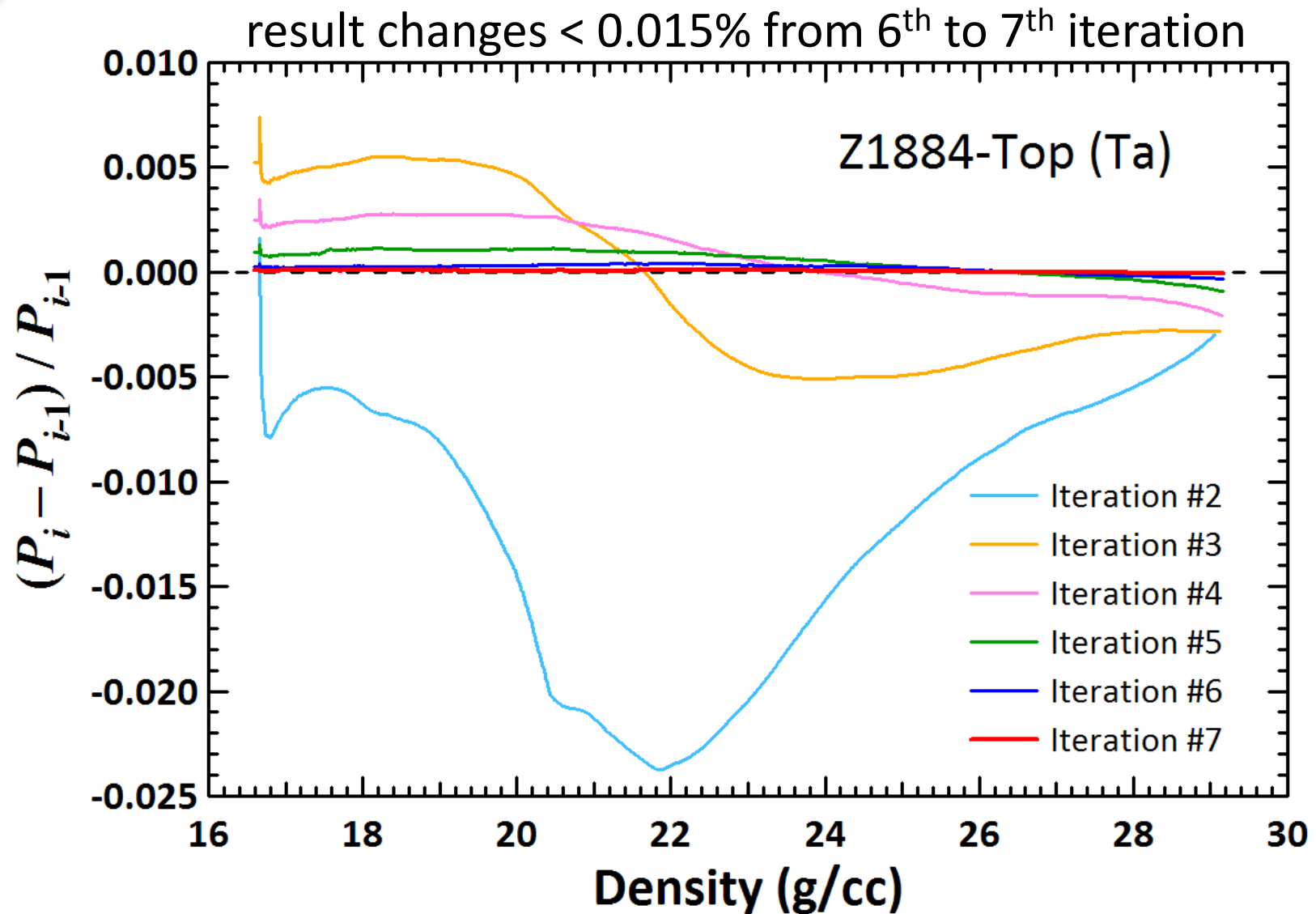
- high confidence in aluminum EOS and conductivity models
- high spatial resolution (2.5- μm cells)

Single sample yields quasi-isentrope by iterating inverse Lagrangian analysis with simulated “zero-thickness” velocity

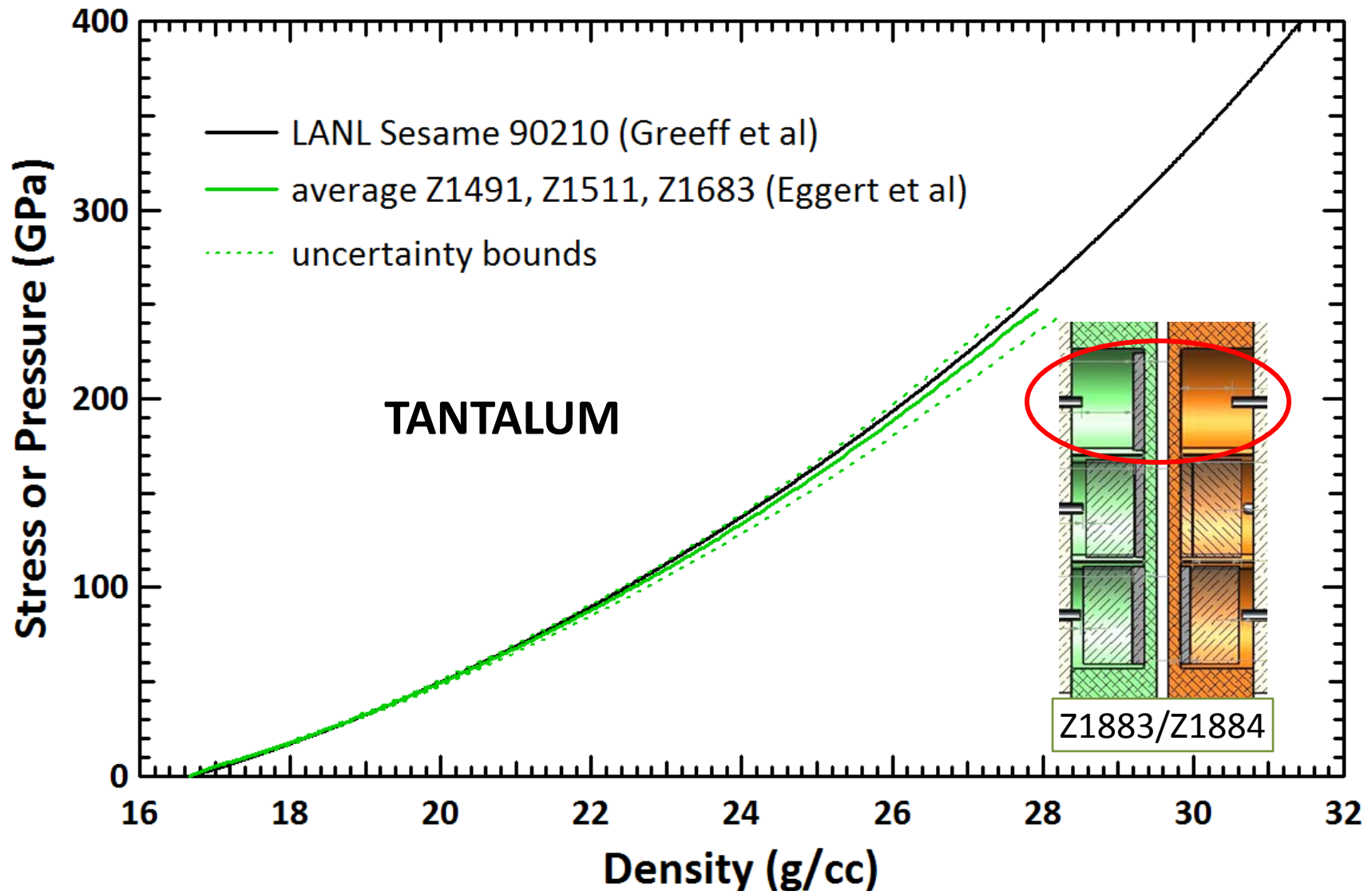
1. measure velocity at back faces of sample and opposite electrode
2. use optimization to determine $B(t)$ from electrode measurement
3. use $B(t)$ and first-guess sample EOS (Sesame table + strength) to simulate electrode/sample interface “zero-thickness” velocity
4. perform inverse Lagrangian analysis on simulated “zero-thickness” velocity and measured back-face velocity of sample
5. convert resulting $\sigma_x(\rho)$ curve to full tabular EOS by assuming constant c_V and Γ/V , equating stress to pressure (strength folded into EOS)
6. use $B(t)$ and new tabular EOS to simulate electrode/sample interface
7. repeat steps 4-6 until material response converges



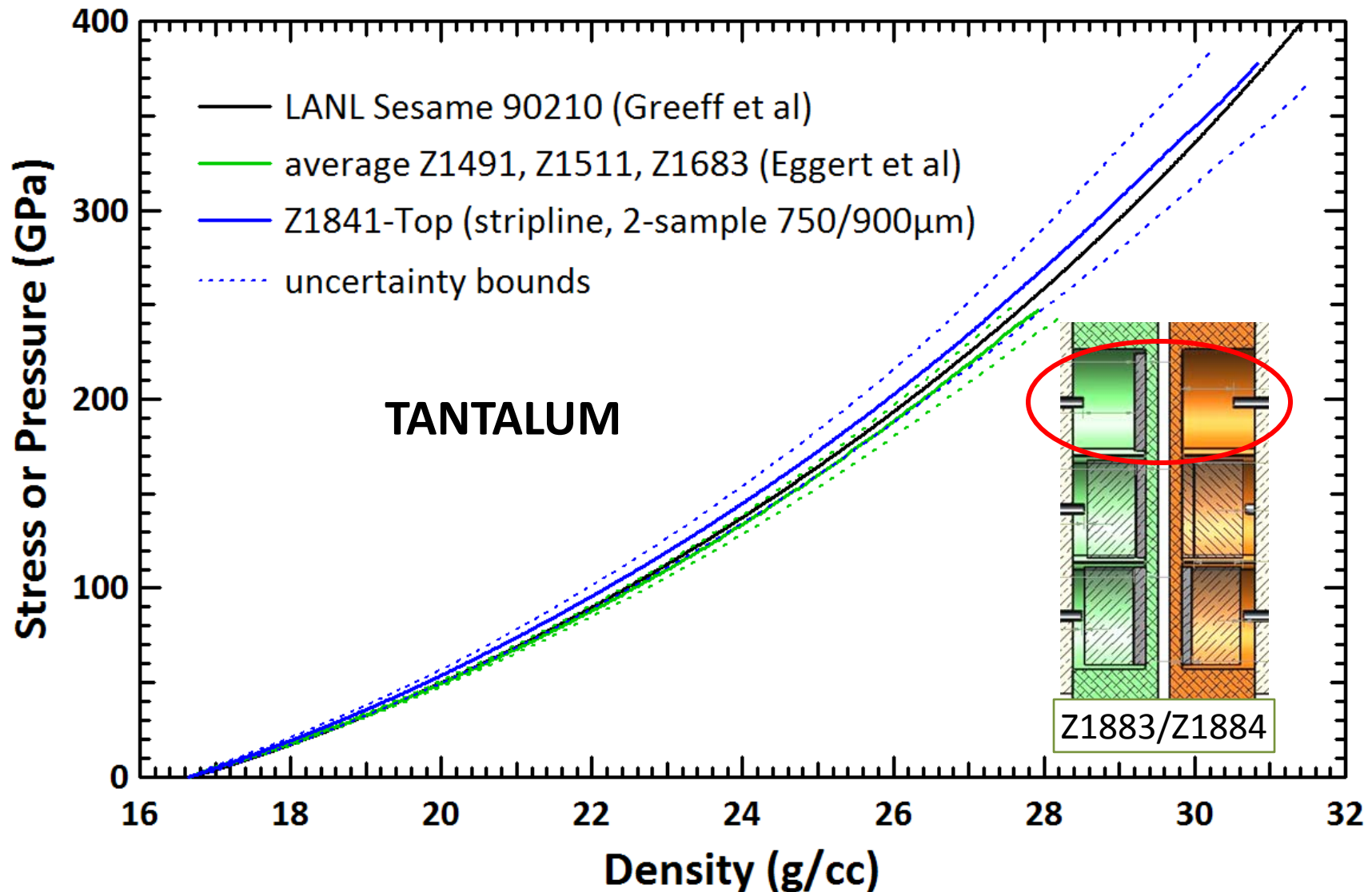
Outer loop of single-sample approach converges



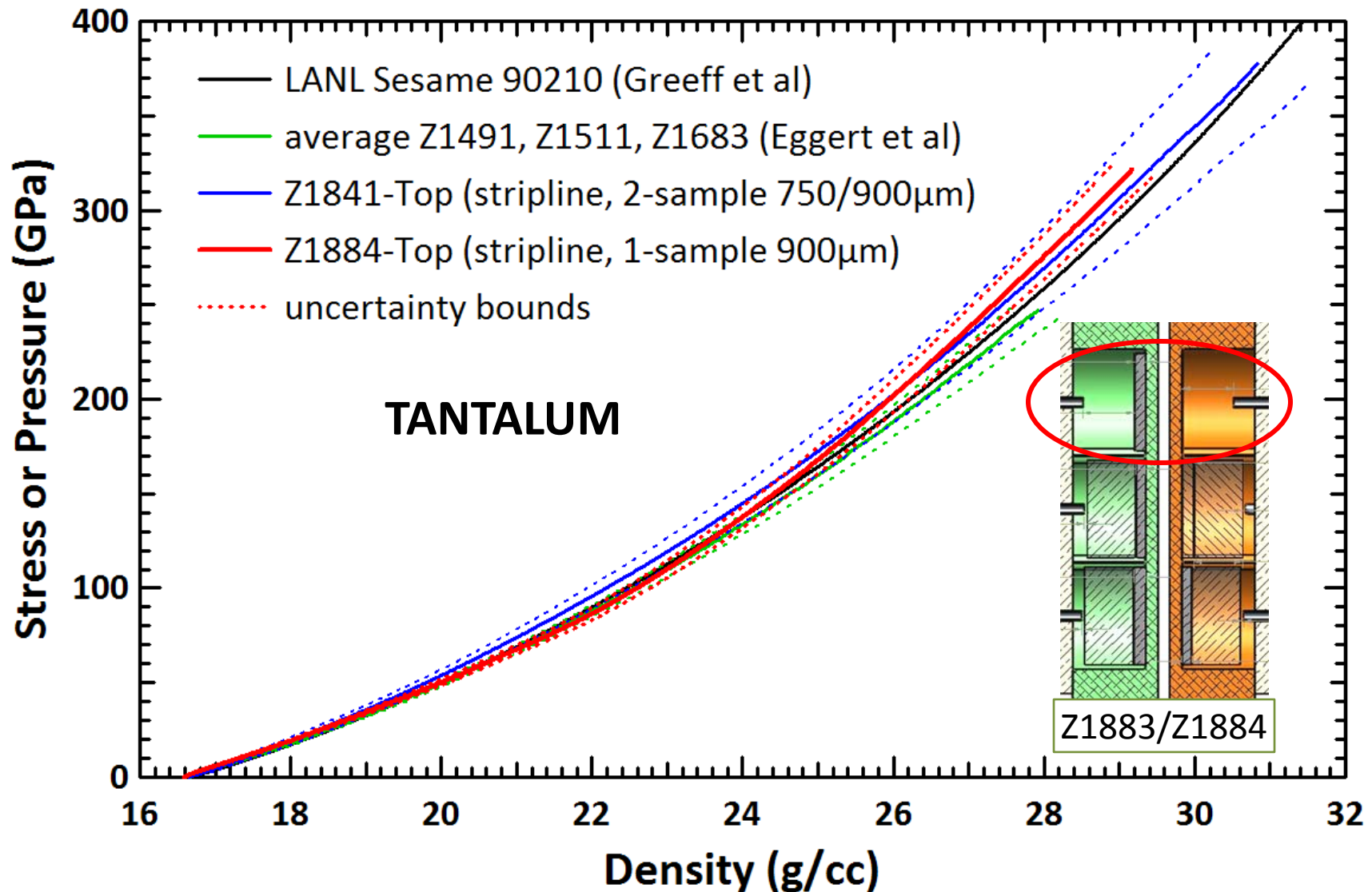
Single-sample measurement of tantalum to 320 GPa decreases uncertainty over two-sample measurement



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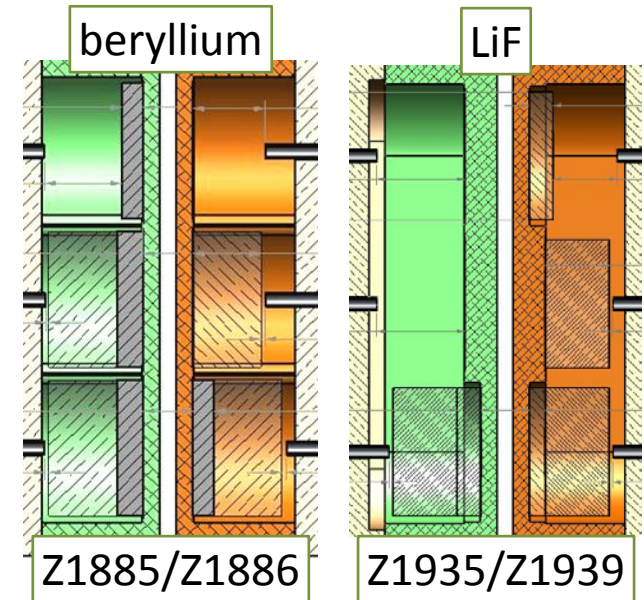


Single-sample measurement of tantalum to 320 GPa decreases uncertainty over two-sample measurement



Further work is planned to fully establish a capability for multi-megabar ramp compression measurements

- Analyze additional single-sample and two-sample data sets on Ta, Be, LiF, Al, Cu, and Au
- Use independently measured strength to correct quasi-isentrope to isentrope
- Extract LiF index-of-refraction window correction
- Quantify sensitivity of results to
 1. aluminum EOS used for B-field optimization
 2. LiF EOS used for windowed samples
 3. B-field gradients across sample diameter



- The stripline load with the single-sample analysis approach has the **potential** to measure quasi-isentropic loading paths to multi-megabar pressures with uncertainties of $\sim 1\%$ in density and $\sim 3\%$ in stress
- Recent design and pulse-shaping improvements suggest measurements to > 5 Mbar are possible on high-Z materials at full machine charge voltage